

<b>Notice of References Cited</b>	Application/Control No. 10/017,212		Applicant(s)/Patent Under Reexamination WODZIANEK ET AL.	
	Examiner Eleni A Shiferaw		Art Unit 2136	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0090939 A1	07-2002	Howard, Newton	455/422
*	B	US-6,363,423 B1	03-2002	Chiles et al.	709/224
*	C	US-2003/0009687 A1	01-2003	Ferchau et al.	713/200
*	D	US-6,134,593 A	10-2000	Alexander et al.	709/229
*	E	US-2003/0001012 A1	01-2003	Bermudez, Miguel N.	235/454
*	F	US-6,750,830 B1	06-2004	Teshima et al.	345/1.2
*	G	US-2003/0046337 A1	03-2003	Strahm et al.	709/203
*	H	US-6,675,234 B1	01-2004	Thomsen, Brant D.	710/19
*	I	US-5,960,445 A	09-1999	Tamori et al.	707/203
*	J	US-6,671,809 B1	12-2003	Perona et al.	726/3
*	K	US-6,374,315 B1	04-2002	Okada et al.	710/62
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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